COMPARISON OF THE NEAR-FIELD MEASUREMENTS BETWEEN A COMMERCIAL OPEN-ENDED RECTANGULAR WAVEGUIDE PROBE AND ITS EQUIVALENT PROBE IN SIW TECHNOLOGY

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GOAL AND METHODOLOGY

Study, under the same measurement conditions, the behaviour of a commercial rectangular waveguide probe and its equivalent probe in SIW technology. The near-field measurements obtained with both probes will be compared, and it will be shown that SIW probes present higher spatial resolution than their equivalent commercial probes. To evaluate the possible differences between the SIW probe and the commercial probe, the measurements were obtained with different widths of the scan in x and ydirections and distances between the DUT and the receiver antenna.

NEAR-FIELD MEASUREMENTS OF A PYRAMIDAL HORN

MEASUREMENT SETUP

- DUT: Narda 640 pyramidal horn
- RX1: open-ended SIW
- RX2: commercial open-ended WR-90

Measurement method: planar range Frequency Range: X band

VARIATION: DISTANCE DUT-RX



CONCLUSIONS

- The open-ended SIW probe detects the pyramidal horn E-field distribution.
- When the DUT-RX distance increases, the power focused in the main lobe begins to extend around de aperture, decreasing the resolution measurements.
- The difference between the power level received by the SIW and the commercial probe changes about 20 dB. Not all the received power is delivered to the measure system, because the SIW aperture impedance is not well matched to the TE10 equivalent characteristic impedance.
- The losses of the SIW also cause that the difference between the received power by each probe is more pronounced at the edges of the pyramidal horn aperture, because the level of the received power is too close to the measure device sensibility.

OPEN-ENDED SIW PROBE SIW CHARACTERISTICS

- X-band operation range
- Diameter holes: 1 mm
- Pitch adjacent posts: 2 mm
- Substrate: RO4003C 60 mils

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VARIATION: STEP WIDTH SCAN

DUT-RX distance 2,5 cm, frequency 9 GHz





CONCLUSIONS

- The near-field measurements are more accurate w scan in x and y directions are very close to dimensions, due to less number of samples in a par
- The measurements of the SIW probe present high are more accurate than those of the commercial pr dimensions of the SIW probe are smaller than t about 55 percent lower length, and 10 percent lower
- For the same step width of the scan, the taken sam less overlapped than those by the WR-90 probe, the SIW probe present higher resolution.

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	NEAR-FIELD MEASU MICROSTRIP ANTEN
106,38 mm	MEASUREMENT SETUR
18,90 ml	 DUT: Microstrip antenna array RX1: open-ended SIW RX2: commercial open-ended Measurement Method: planar Frequency Range: X band
	DUT PX distance 1.5 cm ston
	- DOT-IXX distance 1,5 cm, step
<figure></figure>	Image: constrained from the those of the commercial product
	connector, Wilkinson dividers performed with the SIW probe
when the step widths of the the RX antenna aperture articular space region. er resolution and, therefore, probe, because the aperture those of the WR-90 probe, er width.	 The higher the frequency, the microstrip antenna becomes a microstrip patches. SIW supply higher resolution more suitable to measure cirregions of space.
mples by the SIW probe are so the results obtained with	ACKNOWLEDGM
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open-ended SIW probe present higher resolution than be. It was found higher field levels in the proximity of the and microstrip patches when the measurements were

he higher the antenna reflection coefficient is, so the more reflective and the field is accumulated next to the

than those of commercial probes, so SIW probes are ircuits that present abrupt variation of E-field in close

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